

### **REMARKS**

Claims 1-32 are pending. This paper amends objected to claims 14 and 15. The Office Action indicated that claims 1-32 contain allowable subject matter. Remarks are provided below with reference to like titled sections in the Detailed Action section of the Office Action.

#### **Information Disclosure Statement**

The Office Action indicated that certain references were not initialed on the Form PTO-1449 as each item was not identified properly (references C1-C9 not being initialed). A Third Supplemental Information Disclosure Statement is being submitted herewith in which additional identification information is provided on the PTO-1449 form for references C1-C9. Although these references were previously submitted in the pending case, the Applicant has provided copies of the references as originally submitted for the convenience of the Examiner. It is respectfully requested that the Form PTO-1449 is in condition for initialing and such initials are requested.

It is also noted that an additional Fourth Supplemental Information Disclosure Statement is also filed concurrently herewith. This IDS includes one reference (A32) that has been cited more than three months ago by Applicant in related applications and two references (A31 and C11) cited by Examiner Hannaher in related application 10/668,642 less than three months. As such a fee for the Fourth Supplemental Information Disclosure statement is concurrently filed.

#### **Oath/Declaration**

A replacement declaration is submitted herewith including a printed address rather than handsinged address. Applicant respectfully requests that this declaration be entered.

Drawings

A Request for Corrected Drawings and a Submission of Replacement Drawings is submitted herewith. Applicant respectfully requests that these drawings be entered.

Amendment to the Specification

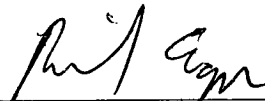
Applicant has amended the Specification to correct typographical errors as identified in the Office Action. Applicant respectfully requests that these amendments be entered.

Claim Objections

Claims 14 and 15 have been subject to an objection related to an antecedent basis. These claims have been amended accordingly. Applicant respectfully requests that these claim amendments be entered.

The examiner is invited to contact the undersigned at the phone number indicated below with any questions or comments, or to otherwise facilitate expeditious and compact prosecution of the application.

Respectfully submitted,



Richard D. Egan  
Registration No. 36,788  
Attorney for Applicant

O'KEEFE, EGAN & PETERMAN  
1101 Capital of Texas Highway South  
Building C, Suite 200  
Austin, Texas 78746  
(512) 347-1611  
FAX: (512) 347-1615



IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Application of: DALE HARRISON

Filed: SEPTEMBER 23, 2003

For: SEMICONDUCTOR PROCESSING TECHNIQUES UTILIZING  
VACUUM ULTRAVIOLET REFLECTOMETER

Serial No.: 10/669,030

Group Art Unit: 2878

Examiner: HANNAHER, C.

Atty Dkt: METR:002

NUMBER: EV559591315US

I hereby certify that this paper or fee is being deposited with the United States Postal Service "EXPRESS MAIL POST OFFICE TO ADDRESSEE" service, postage prepaid, under 37 CFR 1.10 on the date indicated above and is address to: Commissioner of Patents, P.O. Box 1450, Alexandria, VA 22313-1450.

  
Signature

12/29/05  
Date

ATTN: OFFICIAL DRAFTSMAN  
Commissioner For Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

Dear Sir:

**REQUEST FOR CORRECTION OF DRAWINGS**

Please correct FIGS. 18, 19, 20, 21, 22, 24, 25 and 30 of the application drawings as indicated in red ink on the enclosed photocopy.

Respectfully submitted,



Richard D. Egan  
Registration No. 36,788  
Attorney for Applicant

O'KEEFE, EGAN & PETERMAN, LLP  
1101 Capital of Texas Highway South  
Building C, Suite 200  
Austin, Texas 78746  
(512) 347-1611  
FAX: (512) 347-1615

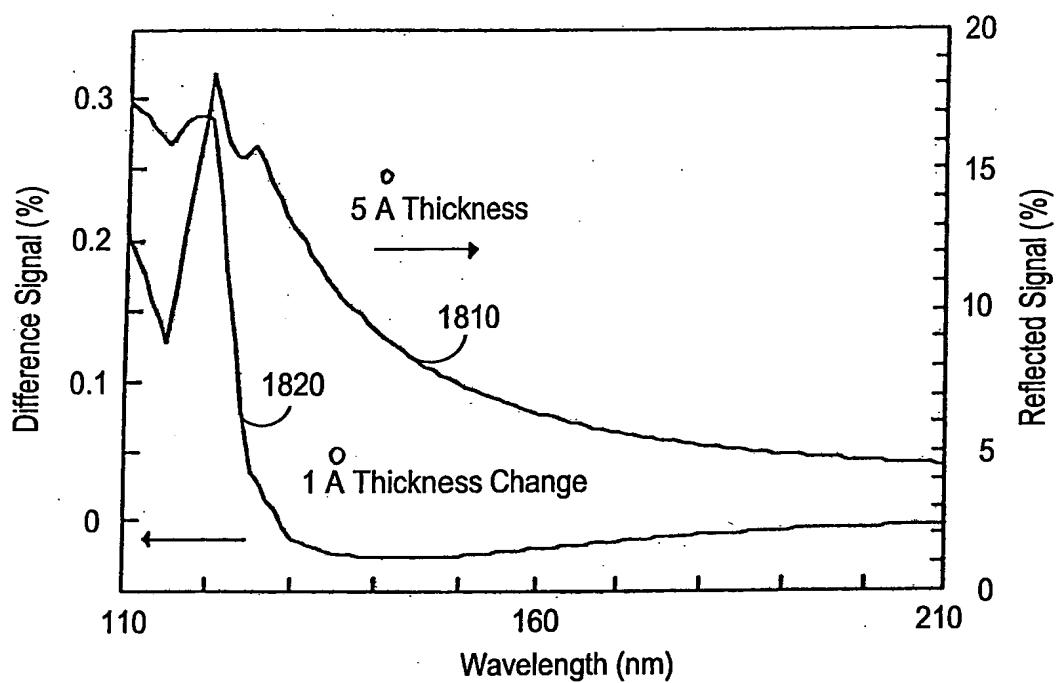


FIG. 18

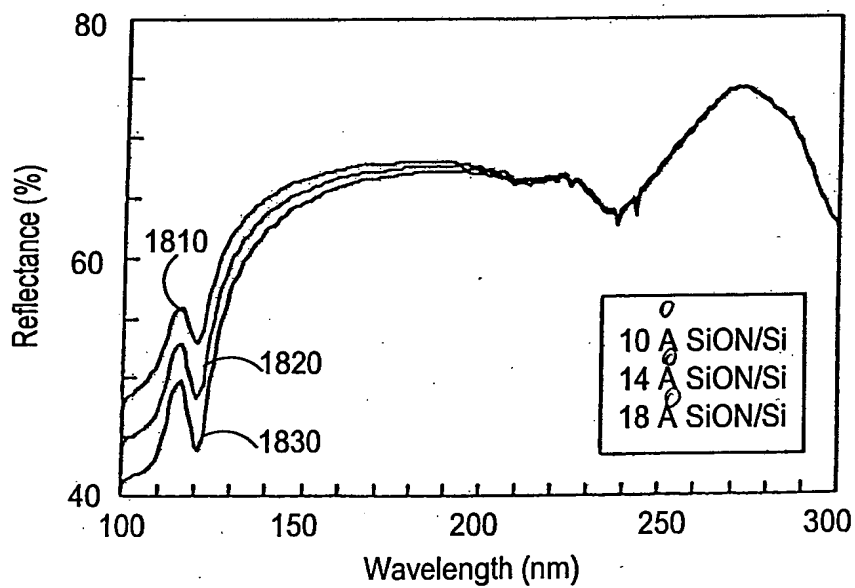


FIG. 19

### 13% N Layer Nitrided Oxide

Thickness Matrix (10-18 Å)

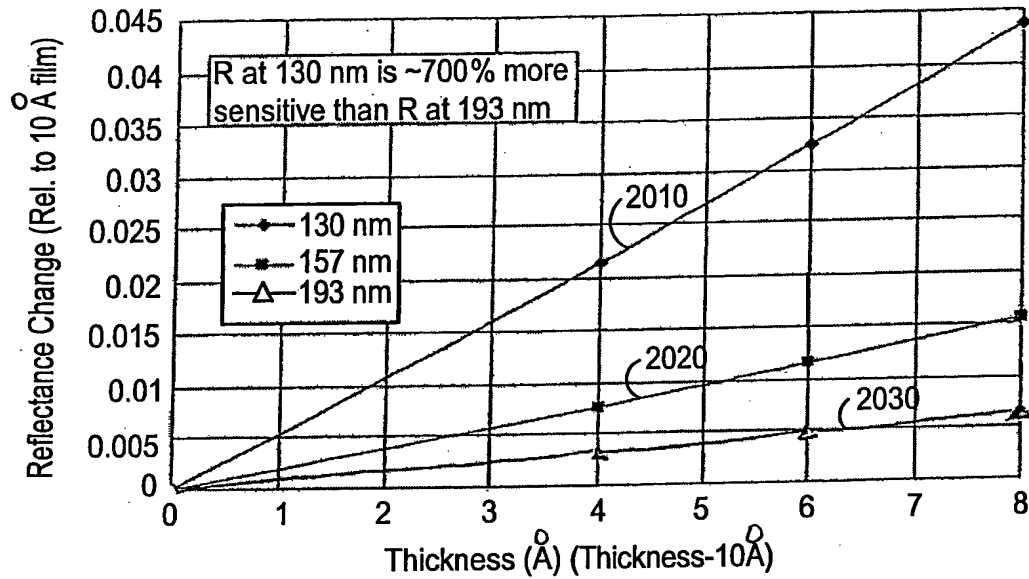


FIG. 20

### 16 Å Layer of Nitrided Oxide

Nitrogen Matrix (10-15%)

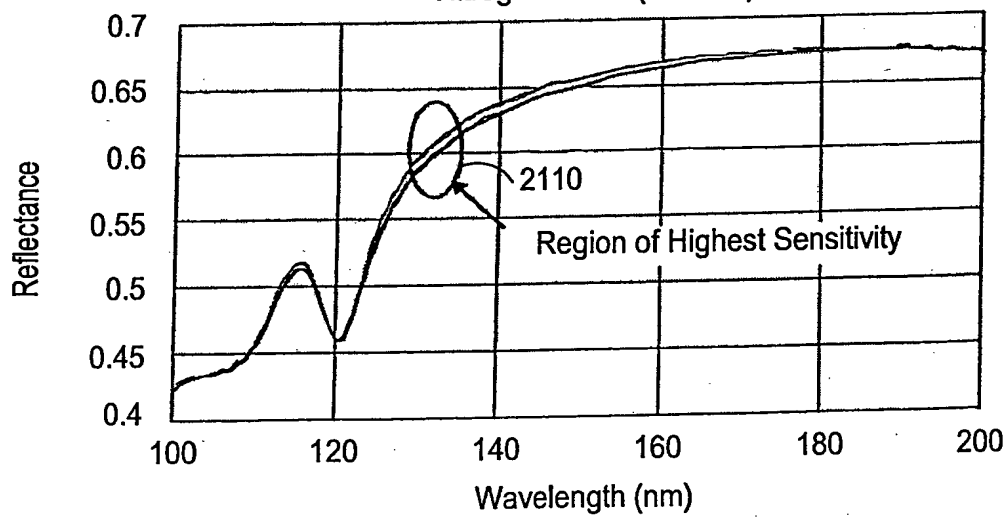


FIG. 21

16 Å Layer Nitrided Oxide  
Nitrogen Matrix (10-15%)

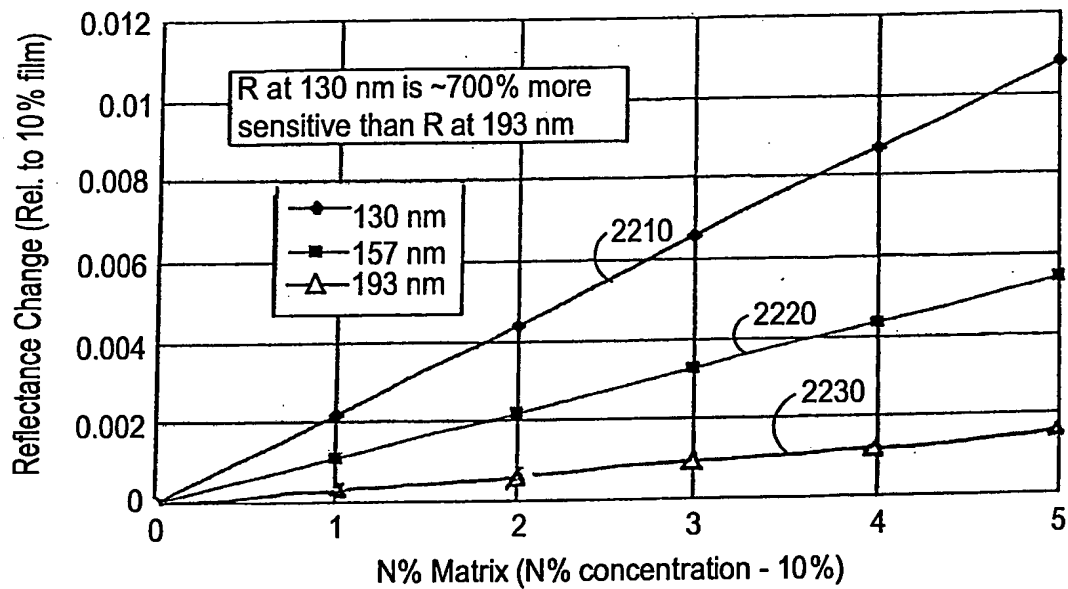


FIG. 22

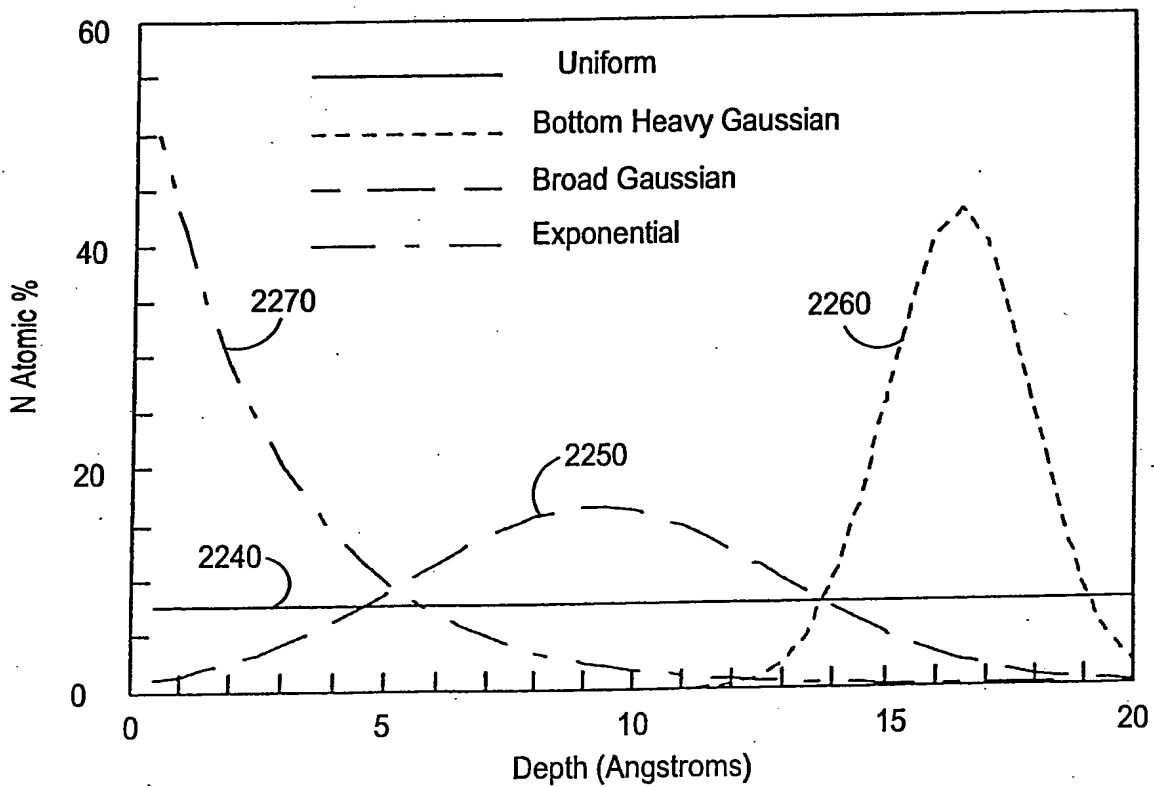


FIG. 22A

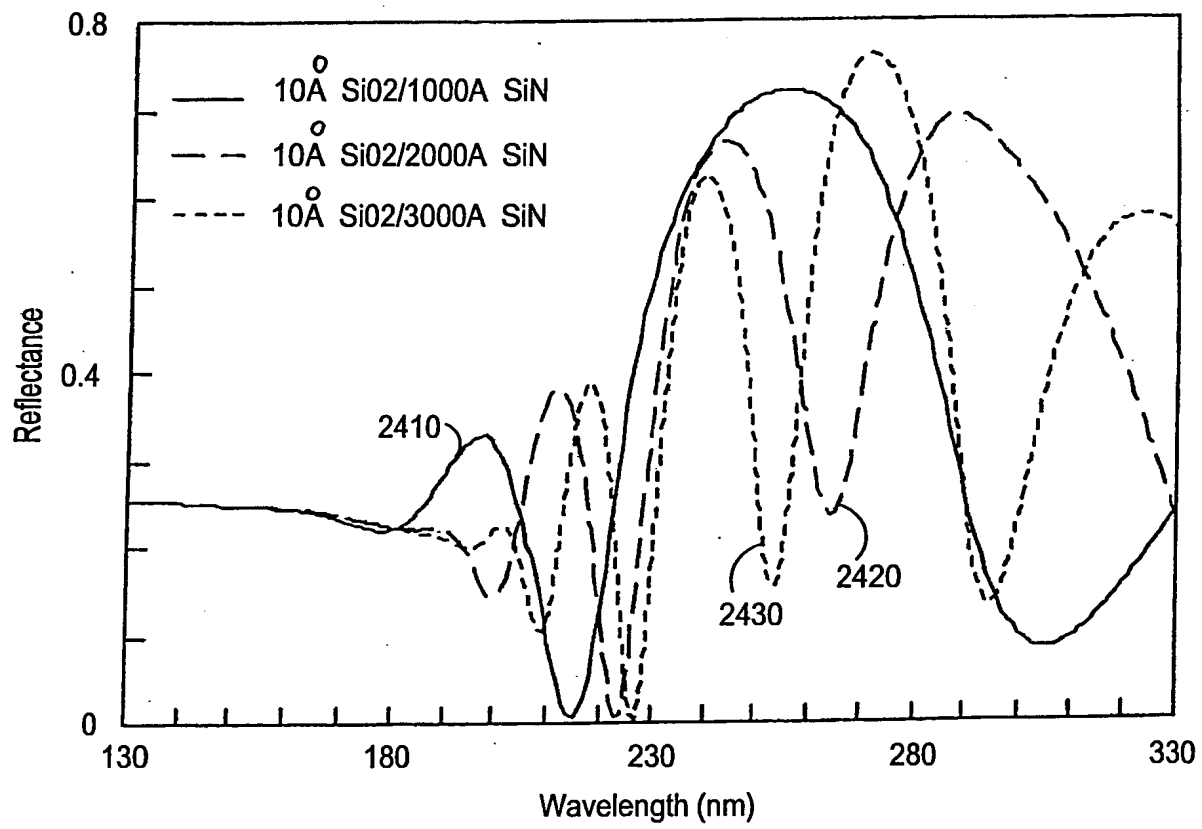


Fig. 24

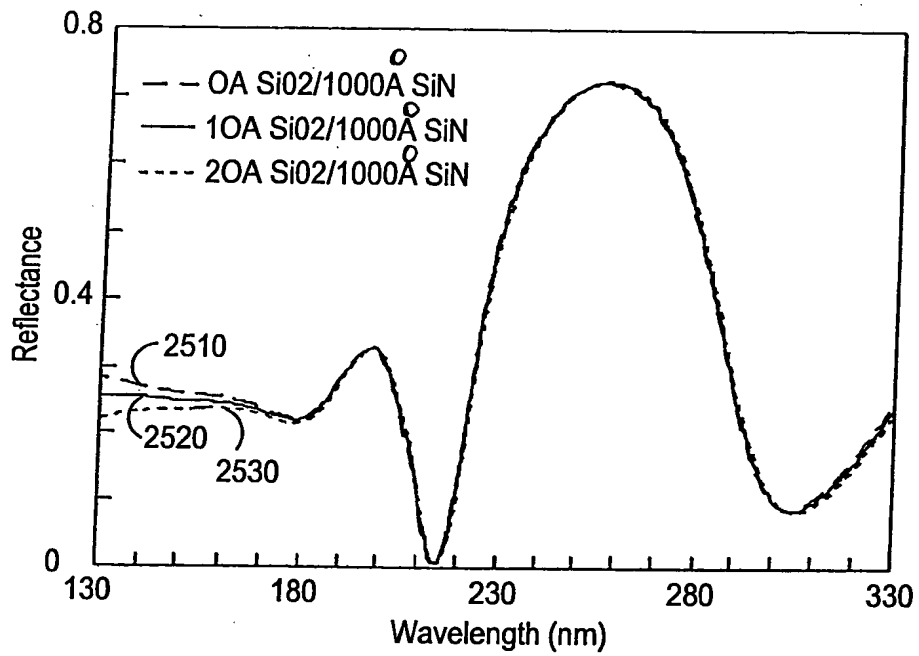


FIG. 25

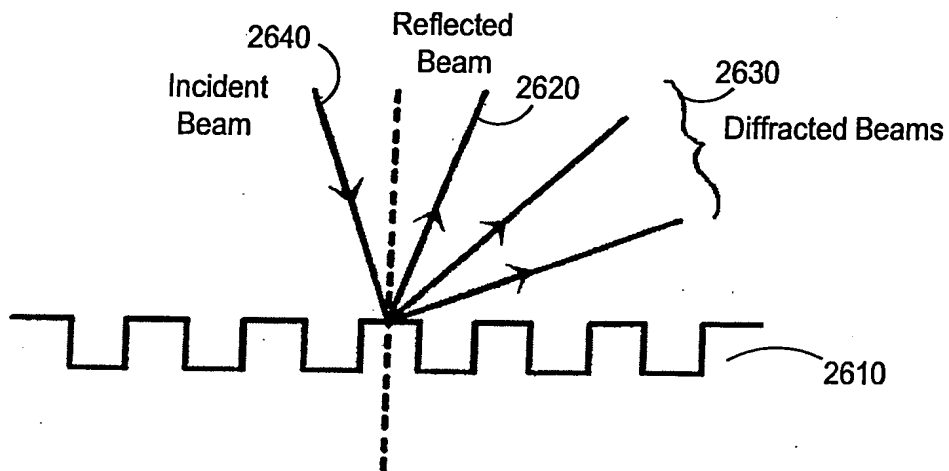


FIG. 26



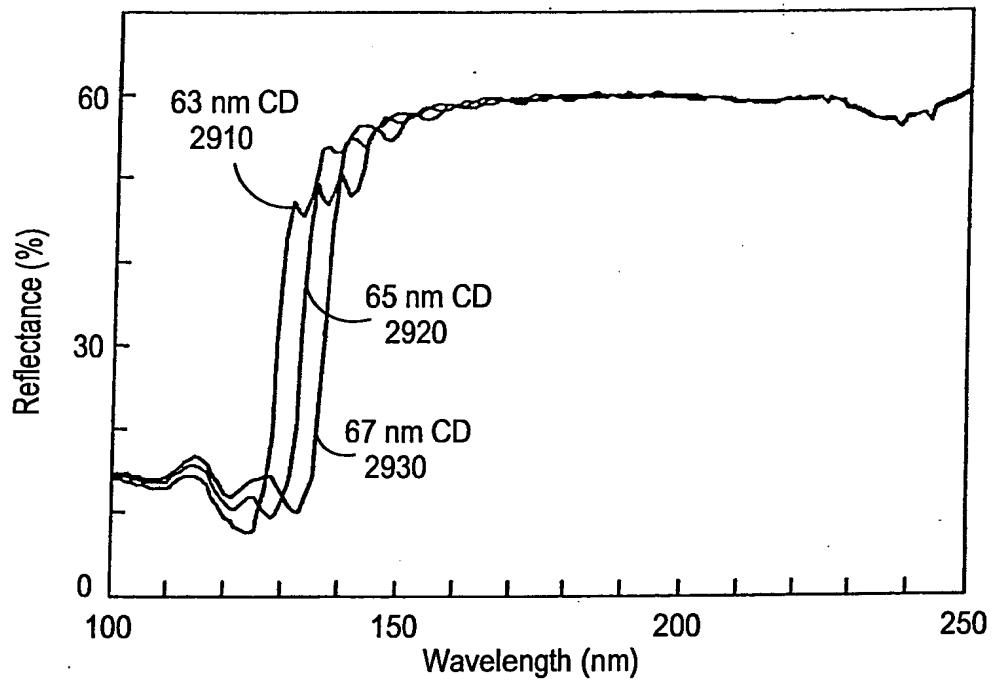


FIG. 29

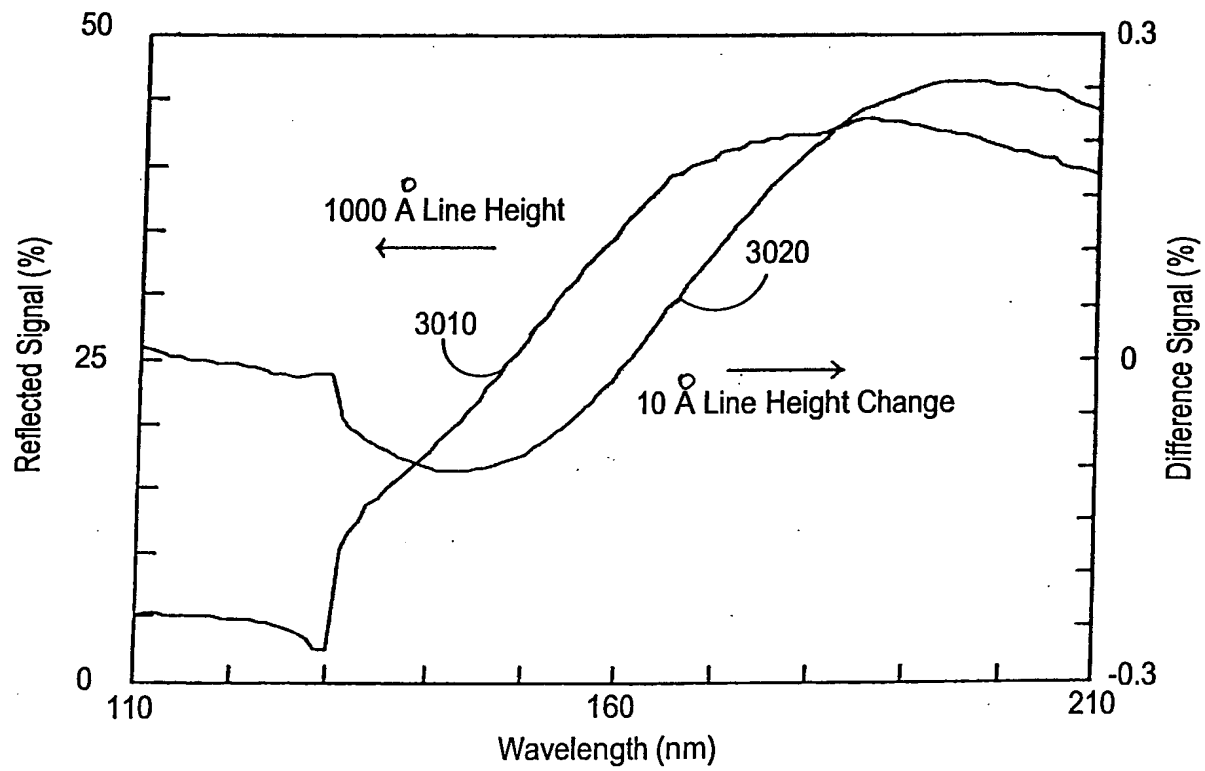


FIG. 30